

## C1210C200FATACTU

Aliases (C1210C200FATAC7800)

SMD Comm X8G HT150C, Ceramic, 20 pF, 1%, 250 VDC, X8G, SMD, MLCC, High Temperature, Ultra-Stable, 1210, 1.5 mm



General Information	
Series	SMD Comm X8G HT150C
Style	SMD Chip
Description	SMD, MLCC, High Temperature, Ultra-Stable
Features	High Temperature, Ultra-Stable
RoHS	Yes
Termination	Tin
Marking	No
AEC-Q200	No
Typical Component Weight	30 mg
Shelf Life	78 Weeks
MSL	1

Dimensions	
Chip Size	1210
L	3.2mm +/-0.2mm
W	2.5mm +/-0.2mm
Т	0.78mm +/-0.10mm
S	1.5mm MIN
В	0.5mm +/-0.25mm

**Packaging Specificat** 

**Packaging Quantity** 

Packaging

	3.2mm +/-0.2mm	Measurement Condition	1 MHz 1.0Vrms
	2.5mm +/-0.2mm	Tolerance	1%
	0.78mm +/-0.10mm	Voltage DC	250 VDC
	1.5mm MIN	Dielectric Withstanding Voltage	625 VDC
	0.5mm +/-0.25mm	Temperature Range	-55/+150°C
		Temp. Coefficient	X8G
ations		Capacitance Change with	30 ppm/C, 1Meg
	T&R, 180mm, Plastic Tape	Reference to +25°C and 0 VDC Applied (TCC)	
	4000		O 10/ 1 MH= 1 O\/rs

**Specifications** 

Capacitance	20 pF
Measurement Condition	1 MHz 1.0Vrms
Tolerance	1%
Voltage DC	250 VDC
Dielectric Withstanding Voltage	625 VDC
Temperature Range	-55/+150°C
Temp. Coefficient	X8G
Capacitance Change with Reference to +25°C and 0 VDC Applied (TCC)	30 ppm/C, 1MegaHz 1.0Vrms
Dissipation Factor	0.1% 1 MHz 1.0Vrms
Aging Rate	0% Loss/Decade Hour: Referee Time is 1000 Hours
Insulation Resistance	100 GOhms

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